



Engineering Village

โดย : จิรวัดน์ พรหมพร

jirawat@book.co.th

แผนกฝึกอบรม

บริษัท บุกโปรโมชัน แอนด์ เซอร์วิส จำกัด

ปรับปรุงครั้งล่าสุด 07/05/50

- ψ เป็นฐานข้อมูลทางด้านวิศวกรรมศาสตร์
- ψ รวบรวมจากวารสาร หนังสือ รวมถึงเอกสารในการประชุม และรายงานทางเทคนิคตามหัวข้อต่างๆ
- ψ ให้ข้อมูลย้อนหลังตั้งแต่ปี 1969 - ปัจจุบัน
- ψ ประกอบด้วยรายละเอียดทางบรรณานุกรมและสาระสังเขป และเอกสารฉบับเต็มแบบ HTML และ PDF
- ψ มีการปรับปรุงข้อมูลทุกๆสัปดาห์

Subject Coverage

- Ψ Nuclear Technology
- Ψ Bioengineering
- Ψ Transportation
- Ψ Chemical and process engineering
- Ψ Light and optical technology
- Ψ Agricultural engineering and food technology
- Ψ Computers and data processing
- Ψ Applied physics
- Ψ Electronics and communications
- Ψ Control
- Ψ Civil
- Ψ Mechanical
- Ψ Material
- Ψ Petroleum
- Ψ Aerospace and automotive engineering

- Browse
- Search
 - Easy Search
 - Quick Search
 - Expert Search
 - Thesaurus Search
 - Ebook Search

Register

Compendex, Inspec, NTIS, US Patents, EP Patents & Referex

The combined Compendex®, Ei Backfile, Inspec® & NTIS™, Patents databases allows for searching on the broadest possible range of topics within the scientific, applied science, technical and engineering disciplines and includes patents, journal articles, proceedings, unclassified government reports, and more. Coverage is from 1884 to present. The databases are updated weekly

[More](#)

Personal Account

[Register](#) or Login:

Username:

Password:

[Login](#)

More Search Sources

SELECT DATABASE

- All Compendex Inspec NTIS
 US Patents EP Patents Referex ?

SEARCH FOR

AND

AND

SEARCH IN

All fields

All fields

All fields

LIMIT BY

All document types

All treatment types

Discipline type not available

All Languages

1884 TO 2007

1 Updates

SORT BY

Relevance Publication year

Autostemming off

[Search](#)

[Reset](#)

Browse Indexes ?

- [Author](#)
- [Author affiliation](#)
- [Controlled term](#)
- [Serial title](#)
- [Publisher](#)

Search Tips

Use truncation (*) to search for words that begin with the same letters.
comput* returns computer, computers, computerize, computerization

Truncation can also be used to replace any number of characters internally.
sul*ate returns sulphate or sulfate

Register

Create Your Personal Account

To obtain your FREE personal account, please complete the form below. Your account will allow you to save searches, save records, and create E-mail Alerts.

*indicate required fields

*Title: 1

*First Name: 2

*Last Name: 2

*E-mail address: 3

Specify a password between 6 and 16 characters.

*Choose a Password: 4

*Confirm password:

Yes, Please send me information about Engineering Village or related products from time to time. The information I have provided here is confidential and it will not be released to a third party.

5

1. ระบุคำนำหน้าชื่อ

2. ระบุชื่อ –สกุล

3. ระบุชื่อ email

4. ระบุรหัสผ่านและยืนยัน

5. คลิก Submit

Browse

Compendex, Inspec, NTIS, US Patents, EP Patents & Referex

The combined Compendex®, Ei Backfile, Inspec® & NTIS™, Patents databases allows for searching on the broadest possible range of topics within the scientific, applied science, technical and engineering disciplines and includes patents, journal articles, proceedings, unclassified government reports, and more. Coverage is from 1884 to present. The databases are updated weekly

[More](#)

Personal Account

[Register](#) or Login:

Username:

Password:

[Login](#)

SELECT DATABASE

- All Compendex Inspec NTIS
 US Patents EP Patents Referex ?

SEARCH FOR

AND

AND

SEARCH IN

All fields

All fields

All fields

LIMIT BY

All document types

All treatment types

Discipline type not available

All Languages

1884 TO 2007

1 Updates ?

SORT BY

Relevance ? Publication year

Autostemming off ?

[Search](#)

[Reset](#)

Browse Indexes ?

- [Author](#)
- [Author affiliation](#)
- [Controlled term](#)
- [Serial title](#)
- [Publisher](#)

Search Tips

Use truncation (*) to search for words that begin with the same letters.
comput* returns computer, computers, computerize, computerization

เลือกไล่เรียงตาม Author, Author Affiliation, Controlled term, Serial title, Publisher

Browse

http://www.engineeringvillage2.org - Lookup - - Microsoft Internet Explorer

Search for: Find Selected index: Author

Click on letter below to browse index:

[A](#) [B](#) [C](#) [D](#) [E](#) [F](#) [G](#) [H](#) [I](#) [J](#) [K](#) [L](#) [M](#) [N](#) [O](#) [P](#) [Q](#) [R](#) [S](#) [T](#) [U](#) [V](#) [W](#) [X](#) [Y](#) [Z](#)

[Aa](#) [Ab](#) [Ac](#) [Ad](#) [Ae](#) [Af](#) [Ag](#) [Ah](#) [Ai](#) [Aj](#) [Ak](#) [Al](#) [Am](#) [An](#) [Ao](#) [Ap](#) [Aq](#) [Ar](#) [As](#) [At](#) [Au](#) [Av](#) [Aw](#) [Ax](#) [Ay](#) [Az](#)

Select terms below to add to search

Connect terms with: AND OR

[Next page](#)

A

- [A](#)
- [A](#) ABDULLIN SH
- [A](#) AL-TURAIGI, MOHAMMED
- [A](#) BECCARA, S.
- [A](#) BIRANG, M.
- [A](#) BRASSARD, L.
- [A](#) CAMPO, MARCUS
- [A](#) DAVIES, PET
- [A](#) DONAU SZP...ER, G.
- [A](#) FAZAN, T.
- [A](#) FEIBELMAN, W.
- [A](#) FERREIRA
- [A](#) FJ
- [A](#) GONZALEZ
- [A](#) GUR'YAN, YU.
- [A](#) KILSHAW, J.
- [A](#) LA GUILLAUME, C. BENOIT
- [A](#) LA GUILLAUME, CLAUDE BENOIT
- [A](#) LAU R
- [A](#) LEE, E.
- [A](#) LONDON
- [A](#) LOPEZ, J.
- [A](#) MANO, T.
- [A](#) MARTIN BERLIN, A.
- [A](#) OP HET VELT
- [A](#) PRUITT, LISA
- [A](#) ROY

1. เลือกตัวอักษรเริ่มต้นชื่อผู้แต่ง

2. เลือกชื่อผู้แต่ง

Easy Search

1

Search

2

1. ใส่คำค้นที่ต้องการสืบค้น

2. คลิก Search

Quick Search

Compendex, Inspec, NTIS, US Patents, EP Patents & Referex

The combined Compendex®, Ei Backfile, Inspec® & NTIS™, Patents databases allows for searching on the broadest possible range of topics within the scientific, applied science, technical and engineering disciplines and includes patents, journal articles, proceedings, unclassified government reports, and more. Coverage is from 1884 to present. The databases are updated weekly

[More](#)

Personal Account

SELECT DATABASE

- All Compendex Inspec NTIS **1**
 US Patents EP Patents Referex ?

SEARCH FOR

2
4 AND
AND

SEARCH IN

All fields **3** ?
All fields
All fields

LIMIT BY

All document types **5** ?
All treatment types **6** ?
Discipline type not available ?
All Languages **7**
 1884 TO 2007
 1 Updates **8** ?

SORT BY

Relevance ? Publication year
 Autostemming off ?

10
Search Reset

Browse Indexes ?

- [Author](#)
- [Author affiliation](#)
- [Controlled term](#)
- [Serial title](#)
- [Publisher](#)

1. ระบุแหล่งข้อมูลที่สืบค้น
2. ใส่คำค้น
3. ระบุเขตข้อมูล
4. ระบุค่าเชื่อม
5. ระบุประเภทเอกสาร
6. ระบุชนิดของเอกสาร
7. เลือกภาษาที่ต้องการ
8. ระบุช่วงเวลา
9. เลือกรูปแบบการแสดงผลลัพธ์
10. คลิก Search

Expert Search

Compendex, Inspec, NTIS, US Patents, EP Patents & Referex

The combined Compendex®, Ei Backfile, Inspec® & NTIS™, Patents databases allows for searching on the broadest possible range of topics within the scientific, applied science, technical and engineering disciplines and includes patents, journal articles, proceedings, unclassified government reports, and more. Coverage is from 1884 to present. The databases are updated weekly

[More](#)

Personal Account

[Register](#) or Login:

Username:

Password:

More Search Sources

[CRC ENgnetBASE](#)

[Reedlink](#)

SELECT DATABASE

All Compendex Inspec NTIS US Patents EP Patents Referex ?

ENTER SEARCH TERMS BELOW

SEARCH FROM

1884 TO 2007
 1 Updates ?

SORT BY

Relevance Publication year
 Autostemming off ?

Search Codes ?

C Compendex I Inspec N NTIS U US Patents E EP Patents R Referex

Field	Code	Field	Code	Field	Code
All fields (C, I, N, U, E)	ALL	Discipline (I)	DI	Patent citation index (U, E)	PCI
Abstract (C, I, N, U, E)	AB	Document type (I)	DT	Patent application country (U, E)	PCO
Accession number (C, I, N)	AN	Patent application date (C, N, U, E)	PA	Patent authority code (U, E)	PAC
Astronomical indexing (I)	AI	ISBN (C, I, R)	BN	ECLA code (E)	PEC
Author/Inventor (C, I, N, U, E, R)	AU	ISSN (C, I)	SN	Patent filing date (U, E)	PFD
Affiliation/Assignee (C, I, N, U, E)	AF	Language (C, I, N)	LA	Patent application number (U, E)	PAM
Availability (N)	AV	Ei main heading (C)	MH	Patent attorney name (U, E)	PAN
Chemical indexing (I)	CI	Material identity number (I)	MI	Publisher (C, I, R)	PN
Classification code (C, I, N)	CL	Monitoring agency (N)	AG	Patent priority information (U, E)	PRN
CODEN (C, I)	CN	Notes (N)	NT	US classification (U)	PUC

Browse Indexes ?

[Author](#)
[Author affiliation](#)
[Controlled term](#)
[Language](#)
[Serial title](#)
[Document type](#)
[Publisher](#)
[Treatment type](#)

1. ระบุแหล่งข้อมูลที่สืบค้น 2. ใส่คำค้น 3. อักษรย่อใช้ระบุ Field ในช่องคำค้น

4. ระบุช่วงเวลา 5. เลือกรูปแบบการแสดงผลลัพธ์ 6. คลิก Search

Thesaurus

Thesaurus

The thesaurus function allows you to identify controlled vocabulary terms, find synonyms and related terms and improve your search strategy with suggested and narrower terms.

Controlled vocabulary terms are used to index articles. Since the thesauri have evolved over time, this function can be used to trace the usage of controlled terms.

[More](#)

Personal Account

[Register](#) or Login:

Username:

Password:

[Login](#)

SELECT DATABASE

Compendex Inspec [?](#)

ENTER TERM

Search Exact Term Browse [?](#)

[Submit](#)

Search Tips

Use "Search" to display controlled vocabulary terms that contain the term that you are searching for as well as broader, narrower and related terms. For example, searching for light rail will retrieve Light rail transit, monorails, railroads, rapid transit, subways, trackless trolleys, trolley cars and urban planning.

Use "Exact Term" if you know a controlled vocabulary term and want go directly to its thesaurus entry which contains broader, narrower and related terms as well as scope notes, prior terms and lead-in terms.

Use "Browse" to scan the thesaurus alphabetically.

All terms have hyperlinks that point to the thesaurus entry.

Clicking a select box will move a term to the Search Box where it can be used to perform a database search using the Boolean operators AND or OR along with Engineering Village Quick Search limits. All controlled terms present in the database have a Select box. Lead-in terms that have never been used as controlled vocabulary terms can not be selected.

1. ใส่คำค้นที่ต้องการ

2. คลิก Submit

Result-Thesaurus

Thesaurus

To add terms to your search, click the box in the Select column.

Click on a hyperlinked term to display its thesaurus entry.

Terms in italics are lead-in terms that point to controlled vocabulary.

Terms with an asterisk are previously used terms that have been replaced by newer terms.

SELECT DATABASE

Compendex Inspec ?

ENTER TERM

diodes

Search Exact Term Browse ?

Submit

Search: diodes

55 matching terms found

Terms

Avalanche diodes
Crystal diodes
Diode amplifiers
Diode transistor logic circuits
Diodes
Direct energy converters
Display devices
Electric breakdown
Electric rectifiers
Electron tube diodes

Select

1

LIMIT BY

All document types ?

All treatment types ?

All languages

1884 TO 2007

1 Updates ?

SEARCH BOX

COMBINE SEARCH WITH

AND OR

SORT BY

Relevance ? Publication year

Search

Reset

Remove

1. เลือกคำค้นที่ต้องการ 2. เลือกประเภทเอกสาร 3. ระบุค่าเชื่อม 4. เลือกภาษา

5. ระบุช่วงเวลา 6. เลือกรูปแบบการแสดงผลลัพธ์ 7. คลิก Search

Ebook Search

Referex

Referex Engineering is a specialized electronic reference product that draws upon hundreds of premium-engineering titles to provide engineering students and professionals with the answers and information they require at school, work, and in practice.

Personal Account

[Register](#) or Login:

Username:

Password:

[Login](#)

More Search Sources

[Compendex](#)

[Inspec](#)

[NTIS](#)

[US Patents](#)

[EP Patents](#)

[CRC ENGnetBASE](#)

[ReedLink](#)

[GlobalSpec](#)

[IHS Standards](#)

CHOOSE COLLECTION

- All Referex Collections ?
- Materials & Mechanical **1**
- Chemical, Petrochemical & Process
- Electronics & Electrical

SEARCH FOR

2
AND
AND

SEARCH IN

 3
Keyword
Keyword

5 [Search](#) [Reset](#)

BROWSE BOOKS BY COLLECTION OR SUBJECT

Materials & Mechanical (155)

[Aeronautical Engineering \(7\)](#)
[Aircraft Design \(6\)](#)
[Automotive Engineering \(10\)](#)
[Biomedical Engineering \(1\)](#)
[Business Strategy and Industrial Engineering \(2\)](#)
[CAD, CAM, CAE \(1\)](#)
[Chemical Engineering \(7\)](#)
[Chemical Health and Safety \(1\)](#)
[Civil Engineering \(2\)](#)
[Computer Aided Design \(5\)](#)

[more...](#)

Electronics & Electrical (138)

[Audio Electronics \(4\)](#)
[Biomedical Engineering \(2\)](#)
[Chemical Health and Safety \(1\)](#)
[Circuit Design \(17\)](#)
[Circuit Theory and Analysis \(6\)](#)
[Communications and Signal Processing \(32\)](#)
[Computer Interfacing \(6\)](#) **6**
[Computing for Engineers \(3\)](#)
[Control Applications \(1\)](#)
[Control Engineering \(6\)](#)

[more...](#)

Chemical, Petrochemical & Process (114)

[Biomedical Engineering \(1\)](#)
[Chemical Engineering \(46\)](#)
[Chemical Health and Safety \(14\)](#)
[Chemistry \(16\)](#)
[Civil Engineering \(1\)](#)
[Control Engineering \(3\)](#)
[Control of Electrical Systems \(3\)](#)
[Design Engineering \(3\)](#)
[Electromagnetics \(1\)](#)
[Energy - General \(1\)](#)

[more...](#)

1. เลือกแหล่งข้อมูลที่สืบค้น

2. ใส่คำค้น

3. ระบุเขตข้อมูล

4. ระบุคำเชื่อม

5. คลิก Search

6. หรือคลิกเลือกรายชื่อหนังสือที่ต้องการ

Search Result

Tags + Groups

Easy Search

Quick Search

Expert Search

Thesaurus

eBook Search

Ask an Expert

Help

Refine Search

1

Within results

Search

Next Page

1-25

go

Results Manager

Select all on page - Select range: to go - Clear all on page - Clear all selections

Choose format: Citation Abstract Detailed record Clear selected records on new search

View Selections

E-Mail

Print

Download

Save to Folder

2

Search Results

66600 records in Compendex, Inspec, NTIS, US Patents, EP Patents & Referex Remove Duplicates - Save Search - Create Alert - RSS ?

nanotechnology

Sort by: Relevance Author

- 1. **Medical nanotechnology in the UK: a perspective from the London Centre for Nanotechnology**
[Horton, M.A.](#) (London Centre for Nanotechnology, Univ. Coll. London, UK); [Khan, A.](#) **Source:** *Nanomedicine: Nanotechnology, Biology and Medicine*, 2, n 1, March 2006, p 42-8
Database: Inspec
[Abstract](#) - [Detailed](#) - [Full-text](#)
- 2. **Mapping nanotechnology patents: The EPO approach**
[Scheu, M.](#) (European Patent Office, Rijswijk, Netherlands); [Veefkind, V.](#); [Verbandt, Y.](#); [Galan, E.M.](#); [Absalom, R.](#); [Forster, W.](#) **Source:** *World Patent Information*, v 28, n 3, Sept. 2006, p 204-11
Database: Inspec
[Abstract](#) - [Detailed](#) - [Full-text](#)
- 3. **The amazing world of nanotechnology**
[Katzel, J.](#) **Source:** *Control Engineering*, v 53, n 7, July 2006, p 66-71
Database: Inspec
[Abstract](#) - [Detailed](#)

3

4

5

Refine Results

Database

[Compendex](#) (27664)

[Inspec](#) (32320)

[NTIS](#) (1205)

[US Patents](#) (659)

[EP Patents](#) (6661)

[Referex](#) (71)

Author/Inventor

[Cingolani, R.](#) (164)

[Meyyappan, M.](#) (124)

[Ogawa, Kazufumi](#) (116)

[Matsui, S.](#) (113)

[Chen, Y.](#) (103)

[Mirkin, Chad A.](#) (100)

[Ochiai, Y.](#) (97)

[Yitai, Qian](#) (90)

[Ambacher, O.](#) (82)

[Furuva, K.](#) (82)

Author affiliation/Assignee

[Canon Kabushiki Kaisha](#) (513)

[Matsushita Electric Industrial Co., Ltd.](#) (337)

6

1. ปรับปรุงการสืบค้น

2. เลือกจัดการผลลัพธ์

3. แสดงบทคัดย่อ

4. แสดงรายละเอียด

5. Full-text

6. ปรับปรุงผลลัพธ์ตามหัวข้อที่พบ

Results Manager

Select all on page - Select range: to go - Clear all on page - Clear all selections

Choose format: Citation Abstract Detailed record Clear selected records on new search

2

View Selections

E-Mail

Print

Download

Save to Folder

Search Results

68600 records in Compendex, Inspec, NTIS, US Patents, EP Patents & Referex [Remove Duplicates](#) - [Save Search](#) - [Create Alert](#) - [RSS](#) ?

[nanotechnology](#)

Sort by: Relevance [Author](#)

1. **Medical nanotechnology in the UK: a perspective from the London Centre for Nanotechnology**
[Horton, M.A.](#) (London Centre for Nanotechnology, Univ. Coll. London, UK); [Khan, A.](#) **Source:** *Nanomedicine: Nanotechnology, Biology and Medicine*, v 2, n 1, March 2006, p 42-8
Database: Inspec
[Abstract](#) - [Detailed](#) - [Full-text](#)
2. **Mapping nanotechnology patents: The EPO approach**
[Scheu, M.](#) (European Patent Office, Rijswijk, Netherlands); [Veefkind, V.](#); [Verbandt, Y.](#); [Galan, E.M.](#); [Absalom, R.](#); [Forster, W.](#) **Source:** *World Patent Information*, v 28, n 3, Sept. 2006, p 204-11
Database: Inspec
[Abstract](#) - [Detailed](#) - [Full-text](#)
3. **The amazing world of nanotechnology**
[Katzel, J.](#) **Source:** *Control Engineering*, v 53, n 7, July 2006, p 66-71
Database: Inspec
[Abstract](#) - [Detailed](#)

Refine Results

? Help

Database

[Compendex](#) (27684)

[Inspec](#) (32320)

[NTIS](#) (1205)

[US Patents](#) (659)

[EP Patents](#) (6661)

[Referex](#) (71)

Author/Inventor

[Cingolani, R.](#) (164)

[Meyyappan, M.](#) (124)

[Ogawa, Kazufumi](#) (116)

[Matsui, S.](#) (113)

[Chen, Y.](#) (103)

[Mirkin, Chad A.](#) (100)

[Ochiai, Y.](#) (97)

[Yitai, Qian](#) (90)

[Ambacher, O.](#) (82)

[Furuya, K.](#) (82)

[more..](#)

Author affiliation/Assignee

[Canon Kabushiki Kaisha](#) (513)

[Matsushita Electric Industrial Co., Ltd.](#)

(337)

1. เลือกรายการที่ต้องการ

2. คลิก View Selections

View Selection

[Tags + Groups](#)

[Easy Search](#)

[Quick Search](#)

[Expert Search](#)

[Thesaurus](#)

[eBook Search](#)

[Ask an Expert](#)

[Help](#)

[Search Results](#)

[New Search](#)

Results Manager

? **Choose format:** Citation Abstract Detailed record Clear selected records on new search

[View Selections](#)

[E-Mail](#)

[Print](#)

[Download](#)

[Save to Folder](#)

[Remove all](#)

Selected Records

1 - 3 of 3 selected records

[Remove](#) 1. **Mapping nanotechnology patents: The EPO approach**

[Scheu, M.](#) (European Patent Office, Rijswijk, Netherlands); [Yeefkind, V.](#); [Verbandt, Y.](#); [Galan, E.M.](#); [Absalom, R.](#); [Forster, W.](#) **Source:** *World Patent Information*, v 28, n 3, Sept. 2006, p 204-11

Database: Inspec

[Full-text](#)

[Remove](#) 2. **The amazing world of nanotechnology**

[Katzel, J.](#) **Source:** *Control Engineering*, v 53, n 7, July 2006, p 6B-71

Database: Inspec

[Remove](#) 3. **Medical nanotechnology in the UK: a perspective from the London Centre for Nanotechnology**

[Horton, M.A.](#) (London Centre for Nanotechnology, Univ. Coll. London, UK); [Khan, A.](#) **Source:** *Nanomedicine: Nanotechnology, Biology and Medicine*, v 2, n 1, March 2006, p 42-8

Database: Inspec

[Full-text](#)

Results Manager

? **Choose format:** Citation Abstract Detailed record Clear selected records on new search

[View Selections](#)

[E-Mail](#)

[Print](#)

[Download](#)

[Save to Folder](#)

[Remove all](#)

Record 2 from Inspec for: nanotechnology, 1790-2007

Check record to add to Selected Records

2. Mapping **nanotechnology** patents: The EPO approach

[Scheu, M.](#) (European Patent Office, Rijswijk, Netherlands); [Veefkind, V.](#); [Verbandt, Y.](#); [Galan, E.M.](#); [Absalom, R.](#); [Forster, W.](#) **Source:** *World Patent Information*, v 28, n 3, Sept. 2006, 204-11

ISSN: 0172-2190 **CODEN:** WPAID2

Publisher: Elsevier, UK

Abstract: As a consequence of large public and private investments in new technologies at the nanoscale, an increase in the filing numbers of European and PCT patent applications related to **nanotechnology** is expected at the European Patent Office (EPO) in the coming years. A strategy has been devised to prepare the EPO for potential impacts this interdisciplinary emerging technology might have on workload per technical field, classification and search. A part of the strategy has been to create an internal working group on **nanotechnology** (NTWG) of patent examiners from different technical fields reflecting the interdisciplinary nature of this 'size' defined emerging field. First results of this NTWG are agreement within the EPO on a definition of **nanotechnology** and the creation of the corresponding tagging system Y01N which enables the monitoring of the evolution of patenting trends in this area of technology. The tags overcome the intrinsic difficulties in retrieving relevant patent publications from the huge amount of information contained in the EPO's patent databases. In addition it is expected that access to Y01N via esp@cenet terms will simplify prior art search of **nanotechnology** patents and will support strategic decision making for economists, investors or funding agencies in **nanotechnology**. [All rights reserved Elsevier] (18 refs.)

Inspec controlled terms: [identification technology](#) - **nanotechnology** - [patents](#)

Classification Code: [C0230B](#) Legal aspects of computing - [C5590](#) Other computer peripheral equipment - [E0270](#) Legal aspects - [E3644T](#) Nanotechnology industry

Add a tag ?

Public

Add

[del.icio.us](#)

[Abstract](#) [Detailed](#) - [Full-text](#)

[Blog This](#)[E-Mail](#)[Print](#)[Download](#)[Save to Folder](#)

Record 2 from Inspec for: nanotechnology, 1790-2007

Check record to add to Selected Records

2. **Accession number:** 9030741

Title: Mapping nanotechnology patents: The EPO approach

Authors: [Scheu, M.](#)¹; [Veeffkind, V.](#)¹; [Verbandt, Y.](#)¹; [Galan, E.M.](#)¹; [Absalom, R.](#)¹; [Forster, W.](#)¹

Author affiliation: ¹ European Patent Office, Rijswijk, Netherlands

Serial title: World Patent Information

Abbreviated serial title: World Pat. Inf. (UK)

Volume: 28

Issue: 3

Publication date: Sept. 2006

Pages: 204-11

Language: English

ISSN: [0172-2190](#)

CODEN: [WPAID2](#)

Document type: Journal article (JA)

Publisher: Elsevier

Country of publication: UK

Material Identity Number: [H383-2006-001](#)

Abstract: As a consequence of large public and private investments in new technologies at the nanoscale, an increase in the filing numbers of European and PCT patent applications related to nanotechnology is expected at the European Patent Office (EPO) in the coming years. A strategy has been devised to prepare the EPO for potential impacts this interdisciplinary emerging technology might have on workload per technical field, classification and search. A

Add a tag ?

Public

Add

[del.icio.us](#)

Mapping nanotechnology patents: The EPO approach

M. Scheu^a, V. Veeffkind^a, Y. Verbandt^a, E. Molina Galan^a, R. Absalom^a and W. Förster^a

^aEuropean Patent Office, P.O. Box 5818, NL-2280 HV Rijswijk, The Netherlands

Available online 21 June 2006.

Abstract

As a consequence of large public and private investments in new technologies at the nanoscale, an increase in the filing numbers of European and PCT patent applications related to nanotechnology is expected at the European Patent Office (EPO) in the coming years. A strategy has been devised to prepare the EPO for potential impacts this interdisciplinary emerging technology might have on workload per technical field, classification and search. A part of the strategy has been to create an internal working group on nanotechnology (NTWG) of patent examiners from different technical fields reflecting the interdisciplinary nature of this 'size' defined emerging field. First results of this NTWG are agreement within the EPO on a definition of nanotechnology and the creation of the corresponding tagging system Y01N which enables the monitoring of the evolution of patenting trends in this area of technology. The tags overcome the intrinsic difficulties in retrieving relevant patent publications from the huge amount of information contained in the EPO's patent databases. In addition it is expected that access to Y01N via esp@cenet terms will simplify prior art search of nanotechnology patents and will support strategic decision making for economists, investors or funding agencies in nanotechnology.

Keywords: Nanotechnology; Nanobiotechnology; Nanooptics; Nanomagnetism; EPO examiners; ECLA; Tagging; Y01N; Interdisciplinary searches; Patent trends

Article Outline

1. Introduction
2. The EPO definition of nanotechnology
 - 2.1. General view on defining nanotechnology
 - 2.2. Nanotechnology tagging: A 'multiple pass' method
 - 2.2.1. First pass

Fulltext : PDF

http://www.sciencedirect.com/science?_ob=MIimg&_imagekey=B6V5D-4K7FJ55-1-K&_cdi=5784&_user=20620 - Microsoft Internet Explorer

Save a Copy Print Search Select Sign

Options x

Bookmarks

Pages

Attachments

Comments

Mapping nanotechnology patents

Introduction

The EPO definition of nanotechnology

General view of nanotechnology patents

Nanotechnology patents: The EPO approach

First pass

Second pass

Third pass

Continuous update

Results

Conclusions

Disclaimer

Acknowledgements

References

ELSEVIER

World Patent Information 28 (2006) 204-211

WORLD PATENT INFORMATION

www.elsevier.com/locate/worpatin

Mapping nanotechnology patents: The EPO approach

M. Scheu *, V. Veefkind, Y. Verbandt, E. Molina Galan, R. Absalom, W. Förster

European Patent Office, P.O. Box 5818, NL-2280 HV Rijswijk, The Netherlands

Abstract

As a consequence of large public and private investments in new technologies at the nanoscale, an increase in the filing numbers of European and PCT patent applications related to nanotechnology is expected at the European Patent Office (EPO) in the coming years. A strategy has been devised to prepare the EPO for potential impacts this interdisciplinary emerging technology might have on workload per technical field, classification and search. A part of the strategy has been to create an internal working group on nanotechnology (NTWG) of patent examiners from different technical fields reflecting the interdisciplinary nature of this 'size' defined emerging field. First results of this NTWG are agreement within the EPO on a definition of nanotechnology and the creation of the corresponding tagging system Y01N which enables the monitoring of the evolution of patenting trends in this area of technology. The tags overcome the intrinsic difficulties in retrieving relevant patent publications from the huge amount of information contained in the EPO's patent databases. In addition it is expected that access to Y01N via esp@cenet terms will simplify prior art search of nanotechnology patents and will support strategic decision making for economists, investors or funding agencies in nanotechnology.

© 2006 Elsevier Ltd. All rights reserved.

Keywords: Nanotechnology; Nanobiotechnology; Nanooptics; Nanomagnetism; EPO examiners; ECLA; Tagging; Y01N; Interdisciplinary searches; Patent trends

Engineering Village

Email Selected Records

Enter the e-mail address where you would like to have your results sent.

To: 1

From: email_service@ei.org

Subject: 2

Message: 3

4

1. ระบุชื่อ E-mail

2. ระบุหัวข้อ

3. ระบุข้อความที่ต้องการส่งพร้อม E-mail

4. คลิก Send E-mail

Medical nanotechnology in the UK: a perspective from the London Centre for Nanotechnology

Horton, M.A. (London Centre for Nanotechnology, Univ. Coll. London, UK); Khan, A. **Source:** *Nanomedicine: Nanotechnology, Biology and Medicine*, v 2, n 1, March 2006, 42-8
ISSN: 1549-9634

Publisher: Elsevier, Netherlands

Abstract: Nanotechnology research is booming worldwide, and the general belief is that medical and biological applications will form the greatest sector of expansion over the next decade, driven by an attempt to bring radical solutions to areas of unmet medical need. What is true in the United States is also being fulfilled in Europe. This, though, is generally at a significantly lower investment level, even if for "large" capital infrastructure and interdisciplinary centers. Against this, the United Kingdom and its European partners are following the maxim "small is beautiful" and are attempting to identify and develop academic research and commercial businesses in areas that traditional nanotechnology developments involving engineering or physics find challenging. Thus in London-University College London (UCL) in a major joint project with Imperial College and linked to other UK and European centers of excellence-we are building upon our internationally competitive medical research (the two universities together form one of the largest centers of biomedical research outside the United States) to focus on and develop medical nanotechnology as a major sector of our research activity. A novel approach to commercialization has been the establishment with government and private equity funds of a "BioNanotechnology Centre" that will act as a portal for UK industry to access specialist skills to solve issues relating to developing nanotechnology-based medical applications, for example, for environmental screening, diagnostics, and therapy. This article reviews our academic and business strategy with examples from our current biomedical research portfolio. [All rights reserved Elsevier] (25 refs.)

Inspec controlled terms: [biotechnology](#) - [nanotechnology](#) - [reviews](#)

Classification Code: [A8783](#) Nanotechnology applications in biomedicine - [A0130R](#) Reviews and tutorial papers; resource letters

Database: Inspec

Download Selected Records

To download records, please select a format below.

1 {

- RIS, EndNote, ProCite, Reference Manager
- BibTex format
- RefWorks direct import
- Plain text format (ASCII)

2

© 2006 Elsevier Inc. All rights reserved.

1. เลือกรูปแบบข้อมูลที่ต้องการดาวน์โหลด

2. คลิก Download

Save to folder

Personal Account Login

You must login to your personal account to save searches, save records, and create E-mail Alerts.

If not, [Register Now](#). It's FREE and allows you to:

E-mail address: **1**

Password:

2 Login

If you have forgotten your password, click [here](#) and we will send you your password.

- Get Weekly Email Alerts
- Save Records
- Save Searches
- Create Folders

My Folders

With your Personal Account, you can create up to three folders in which to save selected records. Each folder can contain up to 50 records.

To create a new folder, please enter a folder name:

3

4

Save Cancel

1. ระบุชื่อ E-mail และ Password

2. คลิก Login

3. ระบุชื่อหัวเรื่องที่ต้องการ Save

4. คลิก Save



Engineering Village